DATA SHEET



MOS FIELD EFFECT TRANSISTOR μ PA1873

N-CHANNEL MOS FIELD EFFECT TRANSISTOR FOR SWITCHING

DESCRIPTION

The μ PA1873 is a switching device which can be driven directly by a 2.5 V power source.

This device features a low on-state resistance and excellent switching characteristics, and is suitable for applications such as power switch of portable machine and so on.

FEATURES

- 2.5 V drive available
- Low on-state resistance

RDS(on)1 = 23.0 m Ω MAX. (Vgs = 4.5 V, ID = 3.0 A)

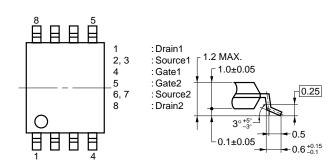
 $R_{DS(on)2} = 24.0 \text{ m}\Omega$ MAX. (Vgs = 4.0 V, ID = 3.0 A)

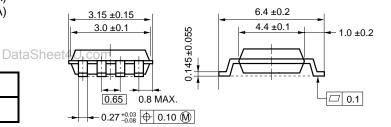
 $R_{DS(on)3} = 28.0 \text{ m}\Omega \text{ MAX.} \text{ (Vgs} = 3.1 \text{ V, ID} = 3.0 \text{ A)}$

 $R_{DS(on)4} = 29.0 \text{ m}\Omega$ MAX. (VGS = 2.5 V, ID = 3.0 A)

· Built-in G-S protection diode against ESD

PACKAGE DRAWING (Unit: mm)





ORDERING INFORMATION

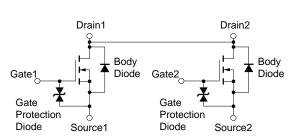
PART NUMBER	PACKAGE
μPA1873GR-9JG	Power TSSOP8

ABSOLUTE MAXIMUM RATINGS (TA = 25°C)

Drain to Source Voltage (Vgs = 0 V)	VDSS	20	V
Gate to Source Voltage (Vps = 0 V)	Vgss	±12	V
Drain Current (DC) (T _A = 25°C)	ID(DC)	±6.0	Α
Drain Current (pulse) Note1	ID(pulse)	±80	Α
Total Power Dissipation (2 unit) Note2	PT	2.0	W
Channel Temperature	Tch	150	°C
Storage Temperature	Tstg	-55 to +150	°C

EQUIVALENT CIRCUIT

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- **Notes 1.** PW \leq 10 μ s, Duty Cycle \leq 1%
 - 2. Mounted on ceramic substrate of 5000 mm² x 1.1 mm

Remark

The diode connected between the gate and source of the transistor serves as a protector against ESD. When this device actually used, an additional protection circuit is externally required if a voltage exceeding the rated voltage may be applied to this device.

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ELECTRICAL CHARACTERISTICS (TA = 25°C)

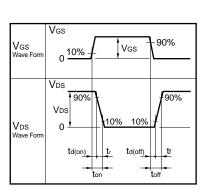
CHARACTERISTICS	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT
Zero Gate Voltage Drain Current	IDSS	Vps = 20 V, Vgs = 0 V			10	μΑ
Gate Leakage Current	Igss	Vgs = ±12 V, Vps = 0 V			±10	μΑ
Gate Cut-off Voltage	V _{GS(off)}	V _{DS} = 10 V, I _D = 1.0 mA	0.5	1.0	1.5	V
Forward Transfer Admittance	yfs	V _{DS} = 10 V, I _D = 3.0 A	5.0			S
Drain to Source On-state Resistance	RDS(on)1	Vgs = 4.5 V, ID = 3.0 A	13.0	18.0	23.0	mΩ
	RDS(on)2	Vgs = 4.0 V, ID = 3.0 A	14.0	19.0	24.0	mΩ
	RDS(on)3	Vgs = 3.1 V, ID = 3.0 A	14.5	21.5	28.0	mΩ
	RDS(on)4	Vgs = 2.5 V, ID = 3.0 A	15.0	24.5	29.0	mΩ
Input Capacitance	Ciss	Vps = 10 V		705		pF
Output Capacitance	Coss	V _G s = 0 V		205		pF
Reverse Transfer Capacitance	Crss	f = 1.0 MHz		145		pF
Turn-on Delay Time	td(on)	V _{DD} = 10 V, I _D = 3.0 A		60		ns
Rise Time	tr	Vgs = 4.0 V		310		ns
Turn-off Delay Time	td(off)	$R_G = 10 \Omega$		380		ns
Fall Time	t _f			420		ns
Total Gate Charge	Q _G	V _{DD} = 16 V		9.0		nC
Gate to Source Charge	Qgs	V _G S = 4.0 V		2.0		nC
Gate to Drain Charge	Q _{GD}	I _D = 6.0 A		4.0		nC
Body Diode Forward Voltage	V _{F(S-D)}	IF = 6.0 A, VGS = 0 V		0.84		V
Reverse Recovery Time	trr	IF = 6.0 A, VGS = 0 V		480		ns
Reverse Recovery Charge	Qrr	di/dt = 50 A / μs		1200		nC

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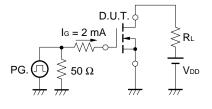
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TEST CIRCUIT 1 SWITCHING TIME

PG. \uparrow R_{G} \uparrow V_{GS} \downarrow 0 $\tau = 1 \mu s$ Duty Cycle \leq 1%

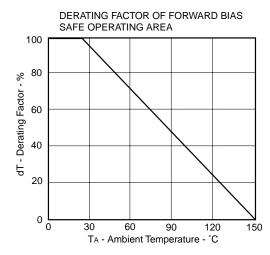


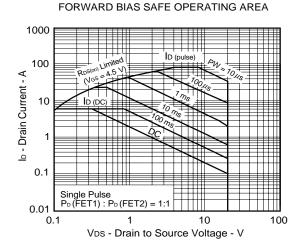
TEST CIRCUIT 2 GATE CHARGE

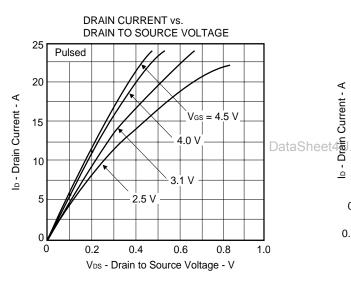


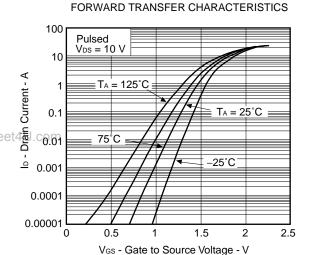
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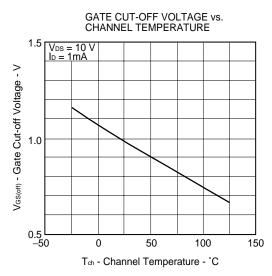
TYPICAL CHARACTERISTICS (TA = 25°C)

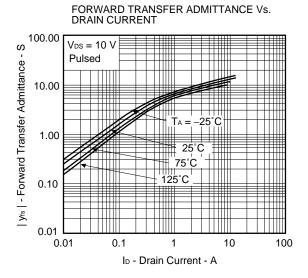






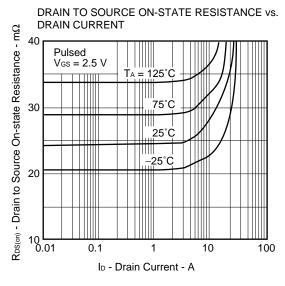


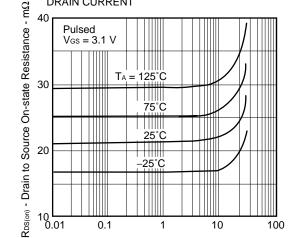




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DRAIN TO SOURCE ON-STATE RESISTANCE vs.

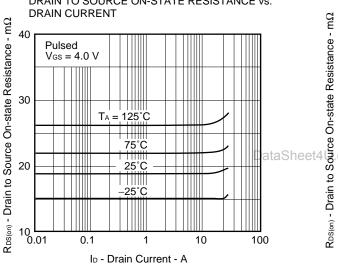
DRAIN CURRENT

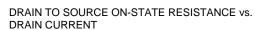
40

0.01

0.1

DRAIN TO SOURCE ON-STATE RESISTANCE vs. **DRAIN CURRENT**

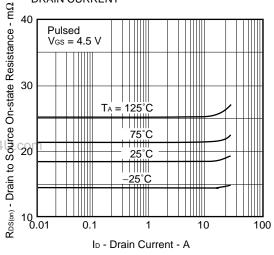




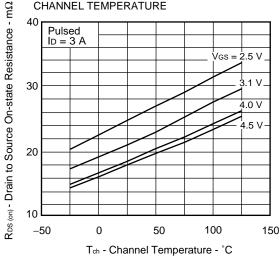
ID - Drain Current - A

10

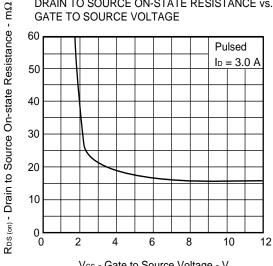
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DRAIN TO SOURCE ON-STATE RESISTANCE vs. CHANNEL TEMPERATURE



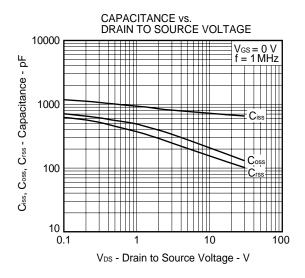
DRAIN TO SOURCE ON-STATE RESISTANCE vs. GATE TO SOURCE VOLTAGE

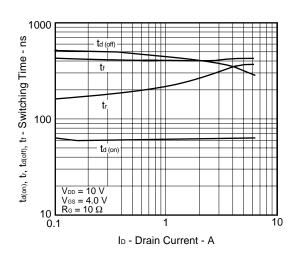


V_{GS} - Gate to Source Voltage - V

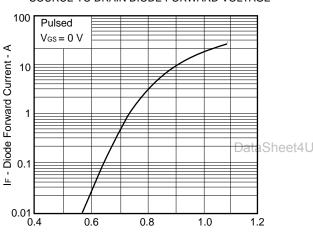
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SWITCHING CHARACTERISTICS

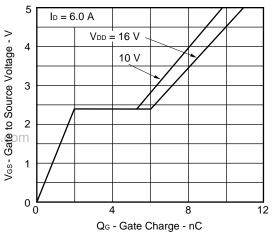




SOURCE TO DRAIN DIODE FORWARD VOLTAGE

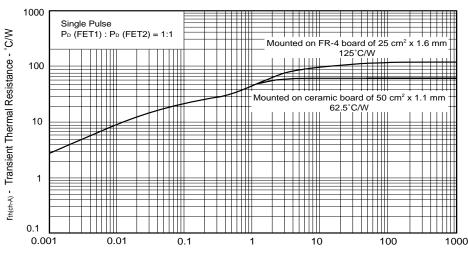






$V_{F(S\text{-}D)}$ - Source to Drain Voltage - V

TRANSIENT THERMAL RESISTANCE vs. PULSE WIDTH



PW - Pulse Width - s

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